

## 1. Description

The 40N06 is the highest performance trench N-ch MOSFETs with extreme high cell density, which provide excellent  $R_{DS(on)}$  and gate charge for most of the synchronous buck converter applications. The 40N06 meet the RoHS and Green Product requirement, 100%EAS guaranteed with full function reliability approved.

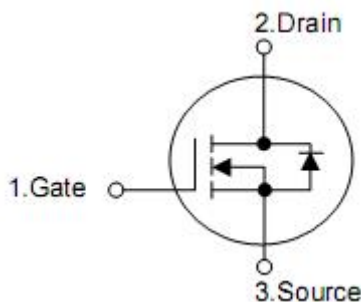
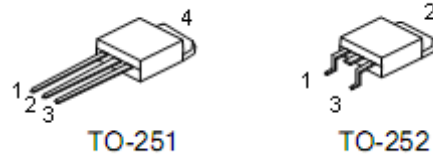
## 2. Features

- n  $R_{DS(on)}=14m\Omega @ V_{DS}=60V$
- n Advanced high cell density Trench technology
- n Super Low Gate Charge
- n Excellent  $C_{dv/dt}$  effect decline
- n 100%EAS Guaranteed
- n Green Device Available

## 3. Applications

- n High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- n Networking DC-DC Power System
- n LCD/LED back light

## 4. Symbol



Pin	Function
1	Gate
2	Drain
3	Source

## 5. Absolute maximum ratings

Parameter	Symbol	Rating	Units
Drain-source voltage	$V_{DS}$	60	V
Gate-source voltage	$V_{GS}$	$\pm 20$	V
Continuous drain current, $V_{GS} @ 10V^1$	$I_D$	$T_C=25^\circ C$	38
		$T_C=100^\circ C$	30
Pulsed drain current <sup>2</sup>	$I_{DM}$	80	A
Single pulse avalanche energy <sup>3</sup>	$E_{AS}$	67	mJ
Avalanche current	$I_{AS}$	28	A
Total power dissipation <sup>4</sup>	$P_D$	45	W
$T_C=25^\circ C$			
Operation junction temperature range	$T_J$	-55 to 150	$^\circ C$
Storage temperature range	$T_{STG}$	-55 to 150	$^\circ C$

## 6. Thermal characteristics

Parameter	Symbol	Typ	Max	Unit
Thermal resistance, Junction-ambient <sup>1</sup>	$R_{\theta JA}$	--	62	$^\circ C/W$
Thermal resistance, Junction-case <sup>1</sup>	$R_{\theta JC}$	--	2.8	

## 7. Electrical characteristics

(T<sub>J</sub>=25°C, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-source breakdown voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	60	-	-	V
BV <sub>DSS</sub> temperature coefficient	ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Reference to 25 °C, I <sub>D</sub> =1mA		0.057		V/°C
Static drain-source on-resistance <sup>2</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =15A		14	18	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A		16	20	
Gate threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.2		2.5	V
V <sub>GS(th)</sub> temperature coefficient	ΔV <sub>GS(th)</sub>			-5.68		mV/°C
Drain-source leakage current	I <sub>DSS</sub>	V <sub>DS</sub> =48V, V <sub>GS</sub> =0V T <sub>J</sub> =25°C			1	μA
		V <sub>DS</sub> =48V, V <sub>GS</sub> =0V T <sub>J</sub> =55°C			5	μA
Gate- source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V			±100	nA
Forward transconductance	g <sub>fs</sub>	V <sub>DS</sub> =5V, I <sub>D</sub> =15A		45		S
Gate resistance	R <sub>g</sub>	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz		1.7	3.4	Ω
Total gate charge(4.5V)	Q <sub>g</sub>	V <sub>DS</sub> =48V, V <sub>GS</sub> =4.5V I <sub>D</sub> =12A	-	17.6		nC
Gate-source charge	Q <sub>gs</sub>			5.35		
Gate-drain charge	Q <sub>gd</sub>			6.81		
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> =15V, I <sub>D</sub> =1A, R <sub>G</sub> =3.3Ω, V <sub>GS</sub> =10V		15.5		ns
Rise time	t <sub>r</sub>			2.2		
Turn-off delay time	t <sub>d(off)</sub>			72.8		
Fall time	t <sub>f</sub>			3.8		
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz		2423		pF
Output capacitance	C <sub>oss</sub>			145		
Reverse transfer capacitance	C <sub>rss</sub>			97		
Single pulse avalanche energy <sup>5</sup>	EAS	V <sub>DD</sub> =25V, L=0.1mH, I <sub>AS</sub> =15A	19			mJ
Continuous source current <sup>1,6</sup>	I <sub>S</sub>	V <sub>G</sub> = V <sub>D</sub> =0V, Force current			38	A
Pulsed source current <sup>2,6</sup>	I <sub>SM</sub>				80	A
Diode forward voltage <sup>2</sup>	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =1A, T <sub>J</sub> =25°C			1	V

Note:1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 20Z copper.

2.The data tested by pulsed, pulse width≤300μs,duty cycle≤2%

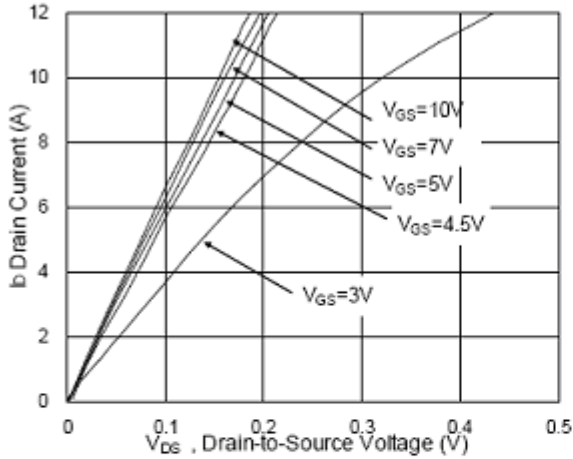
3.The EAS data shows Max.rating.The test condition is V<sub>DD</sub>=25V, V<sub>GS</sub>=10V,L=0.1mH,I<sub>AS</sub>=28A

4.The power dissipation is limited by 150°C junction temperature

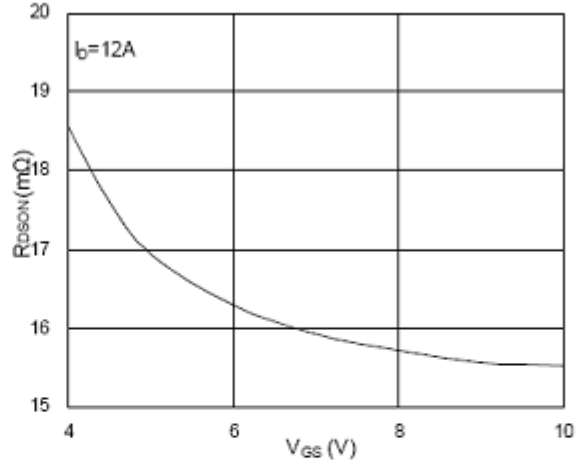
5.The Min, value is 100% EAS tested guarantee.

6.The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>,in real applications, should be limited by total power dissipation.

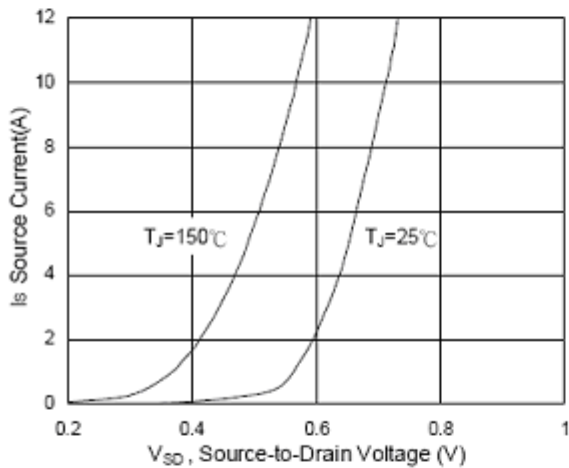
## 8. Test circuits and waveforms



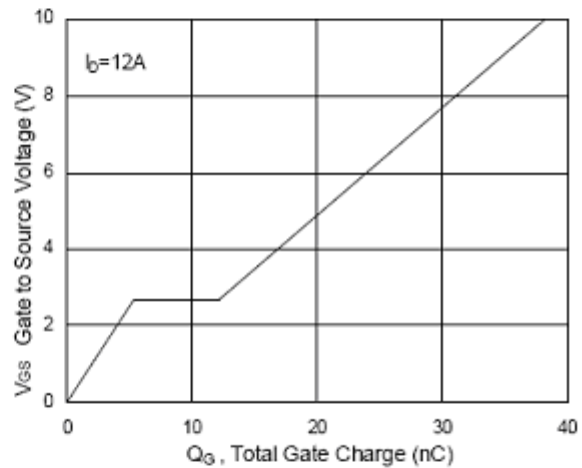
**Fig.1 Typical Output Characteristics**



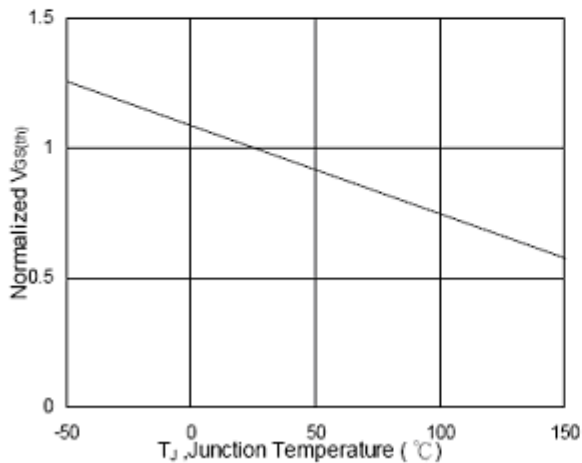
**Fig.2 On-Resistance v.s Gate-Source**



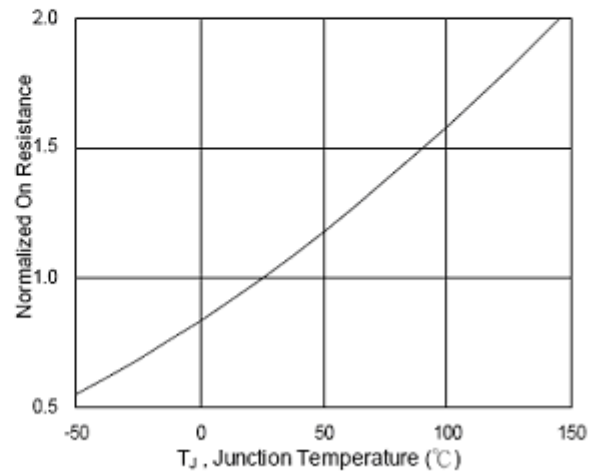
**Fig.3 Forward Characteristics of Reverse**



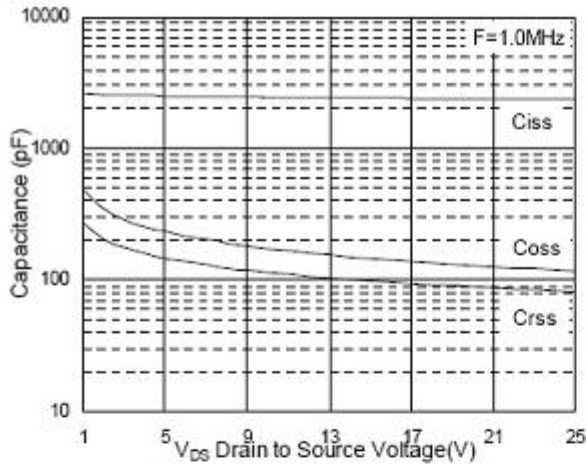
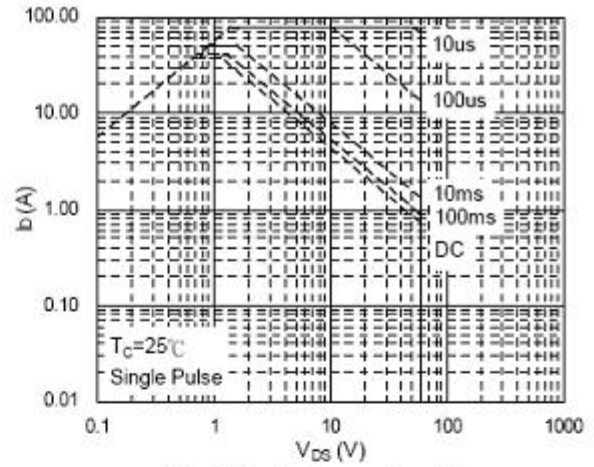
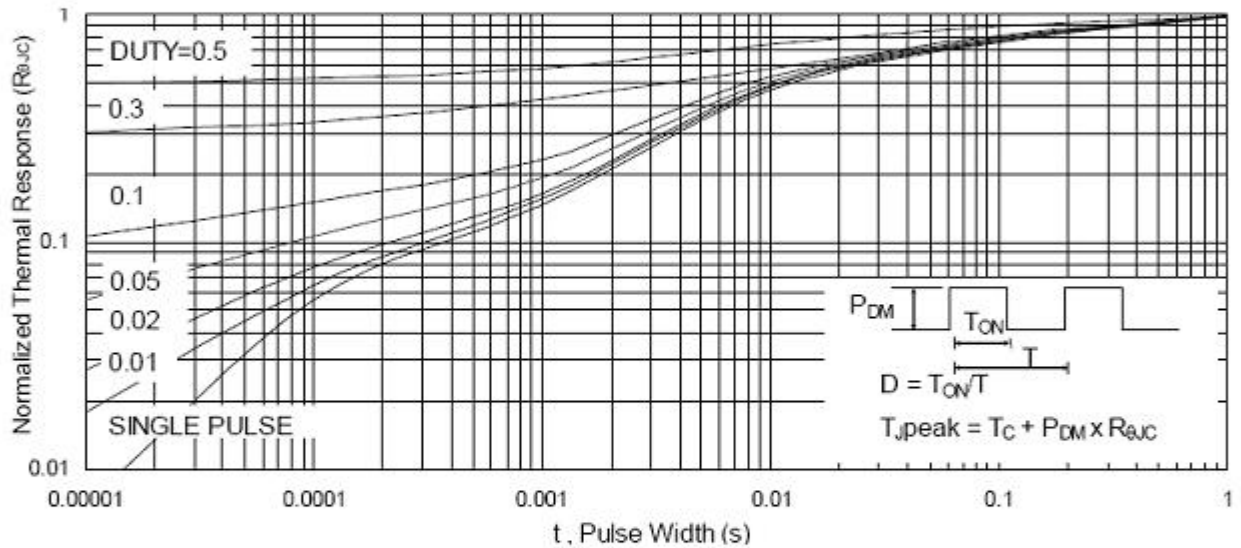
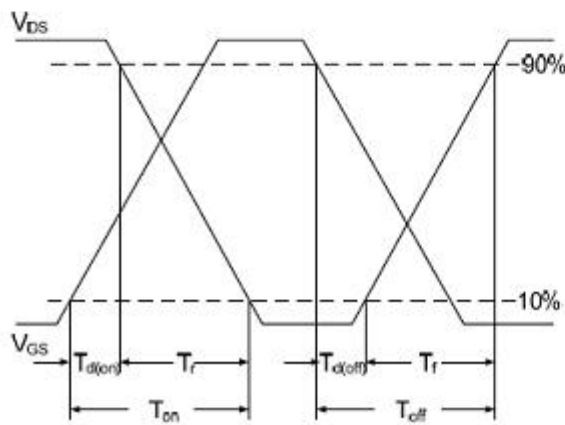
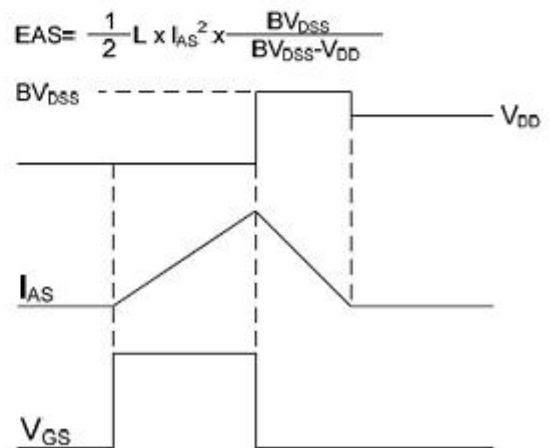
**Fig.4 Gate-Charge characteristics**



**Fig.5 Normalized  $V_{GS(th)}$  v.s  $T_J$**



**Fig.6 Normalized  $R_{DS(on)}$  v.s  $T_J$**


**Fig.7 Capacitance**

**Fig.8 Safe Operating Area**

**Fig.9 Normalized Maximum Transient Thermal Impedance**

**Fig.10 Switching Time Waveform**

**Fig.11 Unclamped Inductive Waveform**